

**IEEE Instrumentation and Measurement Technology Conference**
*A view on the new technologies for instrumentation and measurements*Hilton Sorrento Palace, Sorrento, ITALY
24-27 April 2006 (Monday -Thursday)**Call for Papers**

The conference focuses on all aspects of instrumentation, measurement and control technologies - theory, research and development and applications. Program topics include but are not limited to:

MEASUREMENT SCIENCEMetrology & standards
Measurement principles education**DATA ACQUISITION**Sensors & transducers, smart sensors
Calibration & self-calibration
A/D, D/A & data acquisition
Remote measurements & telemetry
Waveform measurement, analysis & generation
Sensitivity & noise**INSTRUMENTATION TECHNOLOGIES**Automated test & measurement systems
Instrumentation & prototype development
Frequency, microwave and laser I&M systems
Integrated & visual measurement systems
Human-computer interface
Networked & distributed measurements
Autonomous sensing & measurement systems
Non-invasive instrumentation & measurement
Measurement microsystems
Testing & diagnosis of I&M systems
Fault-tolerant & resilient I&M systems**DATA PROCESSING TECHNOLOGIES**Analog, digital & mixed-signal processing
Image processing & imaging systems
Identification, control & distributed monitoring
System prediction & sensor fusion
Soft computing for intelligent I&M systems**PHYSICAL QUANTITIES MEASUREMENTS**Electrical & power measurements
Dielectric, magnetic and EMC measurements
Temperature, moisture & humidity measurements
Mechanical quantities & material analysis
Optical & nuclear measurements
Chemical & biological measurements**MEASUREMENT APPLICATIONS**Robotics, industrial automation & manufacturing
Automotive & transportation
Avionics & aerospace
Environmental monitoring
Medicine & science
Security & biometrics
Telecommunications
Virtual environments

IMTC/06 will offer a day of tutorials on Monday, 24 April. Proposals for tutorial presentations can be submitted before 1 January 2006 to lee.myers@ieee.org.

Authors will submit electronically 1 copy of an extended abstract (3 or 4 pages) *in English*, reflecting new or advanced study, theory or application and including the significance of the contribution, a list of references and figures or tables. Abstracts must be prepared according to the Abstract Preparation Guide and must be accompanied by an Abstract Submission Form. Both documents may be downloaded from the IMTC website – <http://www.ieee-imtc.org> Check the website for all instructions and details. Important dates:

- **3 October 2005** – Abstract submission deadline – submit to lee.myers@ieee.org
- **19 December 2005** – Author notification of acceptance or rejection
- **4 March 2006** – Deadline for receipt of final manuscript

Papers will be reviewed by the IMTC International Program Committee. Authors of accepted abstracts *must guarantee they will register for the conference, pay registration fees, attend and present their papers*. An accepted paper will be published in the proceedings only if the final manuscript is accompanied by registration form(s) and fee(s) for at least one of the authors (*only full member/non-member registration fees will be allowed – no Student or Life Member fees!*). One author registration covers publication of up to 2 accepted papers; each additional paper under the same registration requires a publication fee of US\$50. Authors of accepted and presented papers may submit extended manuscripts to the special issue of *IEEE Transactions on Instrumentation & Measurement* on IMTC/2006, to be published in 2007.

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